

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/995,641	WENDELRUP, HEINO	
Examiner		Art Unit		Page 1 of 1
Eric Elcenko		2643		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0085263	04-2005	Kim et al.	455/556.1
*	B	US-6,915,119	07-2005	Konishi, Masahiro	455/127.1
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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*	A	US-2005/0085263	04-2005	Kim et al.	455/556.1
*	B	US-2002/0089589	07-2002	Adair et al.	348/158
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